	······		·			<del></del>	<u> </u>	
SIPE	Pater	U.S. Department on and Trademark (CUMENTS CITE	Office	CANT	Attomey Doc	ket Number 5051-606		Serial No. 10/669,401
B 2 6 2004	ᆈ	se several sheets if:		CANT				
BADEMARK					Applicants:	Franz	en et al.	h
					Filing Date: Septe	ember 23, 20	03	Group 2878
		U. S. P.	ATENTS & P	ATENT APPL	ICATION PUBL	ICATIONS		
Examiner Initial		Document Number	Date	N	ame	Class	Subclass	Filing Date if Appropriate
oc-	1.	6,143,574	11/7/00	Karlsson et al	•	436	517	
o C	2.	6,127,183	10/3/00	Ivarsson et al.		436	34	
06	3.	5,965,456	10/12/99	Malmqvist et	al.	436	514	
06	4.	5,955,729	9/21/99	Nelson et al.		250	282	
06	5.	5,641,640	6/24/97	Hanning		435	7.92	
		OTHER DOC	UMENTS (II	ncluding Author	, Title, Date, Per	tinent Pages	, Etc.)	
O(L	6.	Hamberg, I.; Hjo	rtsberg, A.; C	Granqvist, C.; A	pplied Physics L	etters 1982, 4	10, 362-364.	
ÐG	7.	Hjortsberg, A.; I	lamberg, I.; C	Granqvist, C. Th	nin Solid Films 1	<b>982, 90</b> , 323	-326.	
06	8.	Szczyrbowski, J.	; Dietrich, A.,	; Hoffman, H. P	hysica Status So	lidi (a) 1983,	<b>78</b> 243-252.	
<i>0</i> ړ.	9.	Brewer, S. H., Free correlation of ref	lectivity, skin	depth, and plas				
06-	10.	Hansen, W. <u>Iour</u>	nal of the Opt	tical Society of	America 1968, 5	8 380-390.		
<u>٥</u>	11.	Fan, J.; Bachner,	F.; Foley, G.	Applied Physic	s Letters 1977, 3	3 <b>1</b> , 773-775.		
Ó.	12.	Stjerna, B.; Olss					3797-3817.	
0C-	13.	Ulman, A. Chem			<del></del>			
66	14.	Lavrich, D.; Wes	terer, S.; Bern	nasek, S.; Scole	s, G. <u>Iournal of I</u>	Physical Cher	nistry B, 199	8, 102, 3456-
<b>6</b> C.	15.	Yan, C.; Zharnik	ov, M.; Golzl	hauser, A.; Grur	ze, M. Langmui	r 2000, 16, 6	208-6215	
OC.	16.	Bain, C.; Biebuy	ck, H.; White	sides, G. Langn	nuir 1989, 5 723	-727.		
· (56	17.	Kohli, P.; Blancl	ard, G. Lang	muir 2000, 16,	8518-8524.			
90	18.	Seip, C.; Talham	, D. Materials	s Research Bull	etin 1999, <b>34</b> 43	7-445.		
00-	19.	Petruska, M.; Ga	***************************************	<del></del>	······		7-189	
90	20.	Allara, D.; Nuzz			· · · · · · · · · · · · · · · · · · ·			
96	21.	Brewer, S.; Fran Surface Adlayer	zen, S; "Indiu	ım Tin Oxide Pl	asma Frequency			

EXAMINER \*EXAMINER

Olel Cale

DATE CONSIDERED 0

08/03/05

1				1				
/	FORM PTO		U.S. Department of Commerce ent and Trademark Office	Attorney Docket Number 5051-606	Serial No. 10/669,401			
	LĬŜ	OF DO	OCUMENTS CITED BY APPLICANT					
n F		g (U	se several sheets if necessary)					
E CO	MADEMARKO	7		Applicants: Franzen et al.				
				Filing Date: September 23, 2003	Group . 2878			
	06	22.	Brewer, S; Brown, D; Franzen, S; "Formatio Oxide: Optical and Electronic Characterization."	•	on Indium-tin			
	00	23.	Allara, D.; Nuzzo, 1985, 1, 45-52.					
	06	24.	SPR - Surface Plasmon Resonance, Surface S	•	SPR-Surface			

**EXAMINER** \*EXAMINER

			\(\frac{1}{2}\)		\		
Substitute	form 1449A/PTO		7		U\ c	omplete if Known	
			DEC 2 ? 20	or <u>.</u>	Application Number	10/669,401	
INFORM	ATION DISCL	OSURE	DEC 5		Filing Date	September 23, 2003	
STATEM	IENT BY APPL	<b>ICANT</b>	\o		First Named Inventor	Franzen et al.	
			TRADE	OFT	Group Art Unit	2878	
(use as ma	ny sheets as nece	essary)	GIRADE		Confirmation No.:	3963	
Sheet	1	of	B1		Attorney Docket Number	5051-606	

			U.S. PATENTS	AND PATENT PUBLICATIONS		
Examiner	Cite No.	U.S. Patent	Document	Name of Patentee or Applicant of Cited  Document	Date of Publication of Cited Document	
Initials*		Number	Kind Code (if known)	Document	MM-DD-YYYY	
06	1.	US-2,340,354		Wells	02/01/44	
<i>3</i> G	2.	US-3,119,355		Gawlitza et al.	01/28/64	
ত উ	3.	US-3,249,741		Mills	05/03/66	
<b>€</b>	4.	US-4,363,955		Gauthier et al.	12/14/82	
<b>∞</b>	5.	US-4,421,015		Masters et al.	12/20/83	
06	6.	US-5,223,290		Alden	06/29/93	
		US-				
		US-				
<del></del>	T	US-				
		US-				
		US-				
		US-				
		US-				
		US-				
		US-				
		US-				
		US-				
		US-			<u> </u>	
		US-				
		US-				

				FOREIGN PA	ATENT DOCUMENTS		
Examiner	Cite	T	Foreign Patent Do	cument	Name of Patentee or Applicant of Cited Date of Publica		Ť
Initials*	Office Number Kind Code (if known)	Document	of Cited Document MM-DD-YYYY				
66-	7.	wo	99/11992		Quadlux, Inc.	03/11/99	
00	6.	wo	01/58269		Fourtec B.V.	08/16/02	
		<del> </del>					
	l	1	OTHE	R NON PATEN	T LITERATURE DOCUMENTS		
Examiner Initials*	Cite No.	serial, s	ymposium, catalog, etc.),	date, page(s), volun	title of the article (when appropriate), title of the item (b ne-issue number(s), publisher, city and/or country whe	re published	T
00	9.	Сору	of International Sea	rch Report for P	CT/US2004/014329; mailed December 8,	2004.	
				····			
		1					

Examiner Signature	Olist	Cal	Date Considered	08/03/	05
ACTIVA A AND ICED. 1 222 4 25 4				D	h = 14 . 41 = -16

INFOR STATE	MENT BY	OISCLOSU APPLICA as necessary	NT MAR D	7 2005
Sheet	1	of	V- C1	79
			<b>Q</b>	E WELL

Complete if Known								
Application Number	10/669,401							
Filing Date	September 23, 2003							
First Named Inventor	Franzen et al.							
Group Art Unit	2878							
Confirmation No.:	3963							
Attorney Docket Number	5051-606							

	······································	Ū.	S. PATENTS	AND PATENT PUBLICATIONS	
Examiner Initials*	Cite No.	U.S. Patent D		Name of Patentee or Applicant of Cited  Document	Date of Publication of Cited Document MM-DD-YYYY
DG	1.	US-6,808,874	B2	Griffiths	10/26/2004
26	2.	US-6,787,647	B1	Milne-Edwards et al.	9/7/2004
0G	3.	US-6,783,672	B2	Tubbs et al.	8/31/2004
<u> </u>	4.	US-6,770,441	B2	Dickinson et al.	8/3/2004
00	5.	US-6,762,025	B2	Cubicciotti et al.	7/13/2004
96	6.	US-6,558,193	B2	Sawayanagi et al.	5/6/2003
06-	7.	US-2002/0102578	A1	Dickinson et al.	8/1/2002
		US-			
	<b>_</b>	US-	<u> </u>	<u> </u>	
	- <b> </b>	US-			
		US-	<del></del>		
		US- US-			
	<del> </del>	US-	<del> </del>		-
		US-	<del></del>		
	+	US-	+		
· <del>····································</del>	<del> </del>	US-	1		

					TENT DOCUMENTS	I Data of Dublication	<del>-</del>	
Examiner Initials*	Cite No.	F	oreign Patent Do		Name of Patentee or Applicant of Cited  Document	Date of Publication of Cited Document	'	
	140.	Office	Number	Kind Code (if known)		MM-DD-YYYY		
	<u> </u>	<u></u>	OTHE	R NON PATENT	LITERATURE DOCUMENTS		*	
Examiner Initials*	Cite No.	serial, sympo	osium, catalog, etc.)	date, page(s), volum	tle of the article (when appropriate), title of the item (t e-issue number(s), publisher, city and/or country whe	re published	Т	
06	8.	Copy of N Internation	lotification of Tra nal Searching A	ensmittal of the li uthority, or the D	nternational Search Report and the Writte eclaration for PCT/US03/30450	n Opinion of the		
	ļ							

										_
Examiner Signature	M	W.	~ 0	ale		Date Considered	68	103	105	
		<del></del>			4 4 1	MOED COO			and nitration i	